Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/742,171	TEIG ET AL.
Examiner	Art Unit
A. M. Thompson	2825

	SEARCHED			
Class	Subclass	Date	Examiner	
716	7	8/1/2005	AMT	
716	9	8/1/2005	AMT	
716	10	8/1/2005	AMT	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
IEEE; USPAT; USPGPUB	8/1/2005	AMT